





SID4-UV-HR

UV WAVEFRONT SENSOR SENSITIVE DOWN TO 190 NM

Based on Phasics patented technology, the SID4 UV-HR wavefront analyzer offers both an unrivalled high resolution (355x280 measurements points) and a very great sensitivity (1 nm RMS) in the ultraviolet spectrum from 190 nm to 400 nm. Consequently, the SID4 UV-HR is perfectly adapted for optical components characterization (used in lithography, semiconductor...) and surface inspection (lens and wafers...).

APPLICATIONS: Laser industry | Astronomy | Semiconductor | Aerospace

SPECIFICATIONS	
Wavelength range	190 - 400 nm
Aperture dimensions	13.8 x 10.88 mm²
Phase spatial resolution	40 µm
Phase & Intensity sampling	355 x 280
Resolution (Phase)	1 nm RMS
Accuracy (Absolute)	10 nm RMS
Acquisition rate	30 fps
Real-time processing frequency	> 3 fps (full resolution)*
Interface	CameraLink
Dimensions	51 x 51.1 x 76 mm ³
Weight	~ 300g
* with SID4 software	

